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Reliability Assessment and Modeling of Optical and Semiconductor Devices

Guest Editors:

Prof. Dr. Ilgu Yun

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Dr. Chang Eun Kim

Dr. Edward Namkyu Cho

Deadline for manuscript submissions:
closed (1 March 2022)

Message from the Guest Editors

Dear Colleagues,

This Special Issue will focus on recent developments in research in optical and semiconductor device reliability, such as reliability assessment, testing, modeling, and failure analysis, for optical and semiconductor devices. In addition, the goal of this Special Issue is to focus on cross-fertilized communication in the state of the art of reliability of optical and semiconductor devices and provide fundamental understanding of basic phenomena that affect reliability.

This special issue mainly focuses on, but not limited to, the following topics:

- Reliability assessment and testing of optoelectronic semiconductor devices;
- Reliability assessment and testing of electronic semiconductor devices;
- Reliability modeling and simulation of optoelectronic semiconductor devices;
- Reliability modeling and simulation of electronic semiconductor devices;
- Reliability methodology and prediction of optoelectronic semiconductor devices;
- Reliability methodology and prediction of electronic semiconductor devices;
- Failure analysis of optoelectronic semiconductor devices;
- Failure analysis of electronic semiconductor devices.

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Editor-in-Chief

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Message from the Editor-in-Chief

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